

FORM PTO-1449 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO.	SERIAL NO.
	10001121-1	00/000,000
	APPLICANT Kenneth P. Park r	
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 Jc971 U.S. PTO
 09/308948


REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
	1A					
	1B					
	1C					
	1D					
	1E					
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	1G					
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	1I					
	1J					
	1K					

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	TRANSLATION	
							YES	NO
	1L							
	1M							
	1N							
	1O							
	1P							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

ED	1Q	"A Logic Design Structure for LSI Testability", E.B. Eichelberger and T.W. Williams, Proc. 14th Design Automation Conf. IEEE Pub. 77CH1216-1C, June 1977, pp 462-468
ED	1R	"The Challenges of Design and Test for the World Wide Web", P. Gelsinger, Proc. International Test Conference, IEEE Pub. 99CH37034, Sept 1999, p 12
ED	1S	"Enhancing Testability of Large; Scale Integrated Circuits Via Test Points and Additional Logic", M.J.Y. Williams and J.B Angell, IEEE Trans. on Computers, Jan 1973, vol C-22, no.1, pp 46-60

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08/22/06

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
	2A					
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	2L							
	2M							
	2N							
	2O							
	2P							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

2Q	"Design for Testability - A Survey", T.W. Williams and K.P. Parker, Proceedings of the IEEE, Jan. 1983, Vol 71, no. 1, pp 98-112
2R	"The Boundary Scan Cell", Texas Instruments, JTAG IEEE 1149.1/P1149.4 Tutorial, Sept. 1997, Tut.I-20, Tut II-24-26
2S	

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